RF Measurement Techniques II

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RF Measurement Instruments

Oscilloscope

Time domain, arbitrary waveforms, direct digitalization

Spectrum analyzer (VSA, FFT)

Frequency domain, down-convert to IF -> digitalization

Vector network analyzer (VNA)

Device (DUT) characterizing, frequency and time domain (via iDFT)

VSA & VNA are based on the super-heterodyne concept

e.g. 97.7-118.7 MHz



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Transmission-lines & VSWR

TEM transmission-lines, e.g. coaxial cable

- Characteristic impedance, typically $Z_0 = 50 \Omega$, is defined by the cross-section geometry.
- Needs to be terminated with $Z_L = Z_0$ to operate without reflections

reflection coefficient:
$$\Gamma = \frac{E^{refl}}{E^{inc}} = \frac{b}{a} = \frac{Z_L - Z_0}{Z_L + Z_0}$$

- For steady-state sinusoidal signals, and $Z_L \neq Z_0$, the superposition of forward (incident) waves (*a*) and backward (reflected) wave (*b*) result in standing waves along the transmission line with voltage maxima V_{max} and minima V_{min} .
- Voltage Standing Wave Ratio (VSWR)

$$VSWR = \frac{|V_{max}|}{|V_{min}|} = \frac{|a| + |b|}{|a| - |b|} = \frac{1 + |\Gamma|}{1 - |\Gamma|}$$



outer

inner

conductor

conductor



S-Parameters – Introduction (1)

Light falling on a car window:

- Some parts of the incident light is reflected (you see the mirror image)
- Another part of the light is transmitted through the window (you can still see inside the car)
- Optical reflection and transmission coefficients of the window glass define the ratio of reflected and transmitted light

Similar: Scattering (S-) parameters of an *n*-port electrical network (DUT) characterize reflected and transmitted (power) waves





S-Parameters – Introduction (2)

Electrical networks

- 1...n-ports circuits
- Defined by voltages $V_n(\omega)$ or $v_n(t)$ and currents $I_n(\omega)$ or $i_n(t)$ at the ports
- Characterized by circuit matrices, e.g. ABCD (chain), Z, Y, H, etc.

RF networks

- 1...*n*-port RF DUT circuit or *S*₁₁ subsystem, e.g. filter, amplifier, transmission-line, hybrid, circulator, resonator, etc.
- Defined by incident $a_n(\omega, s)$ and reflected waves $b_n(\omega, s)$ at a reference plane s (physical position) at the ports
- Characterized by a scattering parameter (S-parameter) matrix of the reflected and transmitted power waves
- Normalized to a reference impedance $\sqrt{Z_0}$ of typically $Z_0 = 50 \Omega$



DUT

1-1' reference plane

(port 1)

S-Parameters allow to

characterize the DUT with

the measurement equipment to be located at some

1-port DUT example

distance

a1

511

 Z_0

b

 a_1

(device under test)

e.g. any

complex

7

load Z

S-Parameters – Example: 2-port DUT



Analysis of the forward S-parameters:

- $S_{11} = \frac{b_1}{a_1}\Big|_{a_2=0} \equiv \text{input reflection coefficient} \\ S_{21} = \frac{b_2}{a_1}\Big|_{a_2=0} \equiv \text{forward transmission gain}$

 - Examples of 2-ports DUT: filters, amplifiers, attenuators, transmission-lines (cables), etc.

ALL ports ALWAYS need to be terminated in their characteristic impedance!

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Dependent parameters:

 $\frac{V_2^{refl}}{\sqrt{Z_0}} = \frac{V_2 - I_2 Z_0}{2 \sqrt{Z_0}}$

S-Parameters – Example: 2-port DUT



Analysis of the reverse S-parameters:

- $S_{22} = \frac{b_2}{a_2}\Big|_{a_1=0} \equiv \text{output reflection coefficient} \\ (Z_L = Z_0 \Rightarrow a_1 = 0) \\ S_{12} = \frac{b_1}{a_2}\Big|_{a_1=0} \equiv \text{backward transmission gain}$
 - n-port DUTs still can be fully characterized with a 2-port VNA, but again: don't forget to terminate unused ports!

 $a_2 = \frac{V_2^{inc}}{\sqrt{Z_0}} = \frac{V_2 + I_2 Z_0}{2\sqrt{Z_0}}$

Dependent parameters:

 $\frac{V_1^{(e)l}}{\sqrt{Z_0}} = \frac{V_1 - I_1 Z_0}{2\sqrt{Z_0}}$

 $\frac{V_2^{refl}}{\sqrt{Z_0}} = \frac{V_2 - I_2 Z_0}{2 \sqrt{7}}$

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$\overline{a}_2|_{a_1=0}$ \equiv forward transmission gain a_1 $a_2 = 0$ \equiv backward transmission gain

 $b_1 = S_{11}a_1 + S_{12}a_2$

 $b_2 = S_{21}a_1 + S_{22}a_2$

S-Parameters – Definition (1) [2-port]

 \equiv input reflection coefficient

 \equiv output reflection coefficient

measurements

impedance

measurements

Linear equations for the 2-port DUT:

with:

 $=\overline{a_1}|_{a_2=0}$

 $a_1=0$

S-Parameters – Definition (2) [n-port]

Reflection coefficient and impedance at the *n*th-port of a DUT:

$$S_{nn} = \frac{b_n}{a_n} = \frac{\frac{V_n}{I_n} - Z_0}{\frac{V_n}{I_n} + Z_0} = \frac{Z_n - Z_0}{Z_n + Z_0} = \Gamma_n$$

$$Z_n = Z_0 \frac{1 + S_{nn}}{1 - S_{nn}} \text{ with } Z_n = \frac{V_n}{I_n} \text{ being the input impedance at the } n^{th} \text{ port}$$

Power reflection and transmission for a *n*-port DUT

 $|S_{nn}|^2 = \frac{\text{power reflected from port } n}{\text{power incident on port } n}$

 $|S_{nm}|^2$ = transmitted power between ports *n* and *m*

with all ports terminated in their characteristic impedance Z_0 and $Z_s = Z_0$ Here the US notion is used, where power = $|a|^2$. European notation (often): power = $|a|^2/2$ These conventions have no impact on the S-parameters, they are only relevant for absolute power calculations

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The Scattering Matrix (1)

Waves traveling towards the *n*-port: (a) = (a₁, a₂, a₂, ... a_n)
 Waves traveling away from the *n*-port: (b) = (b₁, b₂, b₂, ... b_n)

The relation between a_i and b_i (i = 1...n) can be written as a system of n linear equations h_i = the dependent variable.

 $(a_i = \text{the independent variable}, b_i = \text{the dependent variable})$

one - port
$$b_1 = S_{11}a_1 + S_{12}a_2 + S_{13}a_3 + S_{14}a_4 + \dots$$
two - port $b_2 = S_{21}a_1 + S_{22}a_2 + S_{23}a_3 + S_{44}a_4 + \dots$ three - port $b_3 = S_{31}a_1 + S_{32}a_2 + S_{33}a_3 + S_{44}a_4 + \dots$ four - port $b_4 = S_{41}a_1 + S_{42}a_2 + S_{33}a_3 + S_{44}a_4 + \dots$

(S)(a)

in compact matrix form follows



2-Port Examples



Examples of 3-ports



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4-Port Examples

Ideal directional coupler



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S-Parameters – Summary

- Scattering parameters (S-parameters) characterize an RF component or system (DUT) by a matrix.
 - $n \times n$ matrix for *n*-port device
 - Based on incident (a_n) and reflected (b_n) power waves

ALL ports need to be terminated in their characteristic (reference) impedance Z_0

- For a proper S-parameter measurement or numerical computation all ports of the Device Under Test (DUT), including the generator port, must be terminated with their characteristic impedance to assure, waves traveling away from the DUT (b_n-waves) are not reflected twice or multiple times, and convert into a_n-waves. (cannot be stated often enough...!)
- Typically the S-parameters, and therefore the DUT is "measured" and characterized in the frequency domain
 - S-parameters, as wells as DUT circuit elements are described in complex notation with the frequency variable $\omega = 2\pi f$
 - Frequency transformation (iDFT) allows time domain measurements with a "modern" vector network analyzer (VNA).

How to measure S-Parameters?



Performed in the frequency domain

- Single or swept frequency generator, stand-alone or as part of a VNA or SA
- Requires a directional coupler and RF detector(s) or receiver(s)

Evaluate S₁₁ and S₂₁ of a 2-port DUT

- Ensure $a_2 = 0$, i.e. the detector at port 2 offers a well matched impedance
- Measure incident wave a₁ and reflected wave b₁ at the directional coupler ports and compute for each frequency
- Measure transmitted wave b₂ at DUT port 2 and compute



- Evaluate S₂₂ and S₁₂ of the 2-port DUT
 - Perform the same methodology as above by exchanging the measurement equipment on the DUT ports

The Vector Network Analyzer (VNA)



Fun with the VNA!



VNAs vary between manufacturers and models

Concepts and operation is still very similar

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VNA Calibration (1)

- Calibration is not necessary for pure frequency or phase measurements
- Before calibrating the VNA measurement setup, perform a brief measurement and chose appropriate VNA settings:
 - Frequency range (center, span or start, stop)
 - Number of frequency points
 - Can be sometimes increased by rearranging the VNA memory (# of channels)
 - IF filter bandwidth
 - Output power level
 - Calibrate the setup, preferable with an electronic calibration system if more than 2 ports are used!
 - Each port and combination needs to be calibrated, with the cables attached
 - Choose the appropriate connector type and sex
 - The instrument establishes a correction matrix and displays the "CAL" status.





VNA Calibration (2)









Calibration improves the measurement performance

- Return loss improvement by typically 20 dB. Enables mdB accuracy measurements
- Full 2-port or 4-port calibration with manual calibration kits is prone to errors, better use electronic calibration systems.
- Change VNA settings will cause the instrument to inter- and extrapolate, and the calibration status becomes uncertain.

Cables are included in the calibration

- However, changing coaxial connector types not.
- Special VNA cables allows the adaption of different connector types and sex without requiring a re-calibration of the setup!

Synthetic Pulse TD Measurements (1)

Based on an inverse discrete Fourier transformation (iDFT) option in the VNA



- Low-pass mode: Impulse or step response, relying on equidistant samples over the extrapolated (to DC) frequency range.
 - The VNA does not measure at DC!
 - Manually match frequency range and # of points for DC extrapolation, e.g. 1...1000 MHz -> 1001 points, to enable extrapolation exactly to DC, or let the instrument chose the extrapolation settings automatically

Enables time-domain reflectometry (TDR)

- Very useful on portable VNAs, troubleshooting RF cable problems
- Band-pass response (no DC extrapolation)
- Allows time-domain gating and de-embedding of non-resonant subsystems, e.g. measurements on a PCB
- Limited to linear systems
- Select the "real" format for S₁₁ or S₂₁ for time-domain transformations!
 - or dB magnitude to detect small reflections in TDR analysis

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Synthetic Pulse TD Measurements (2)



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An Example – Pillbox* TM₀₁₀ Eigenmode

Characterize the accelerating TM_{010} mode of a cylindrical cavity with beam ports

- The TM₀₁₀ does not have to be the lowest frequency mode
- Compare the measured values of f_{res} , Q_0 and R/Q
 - with an analytical analysis of a perfect cylinder (no beam ports)
 - with a numerical analysis

<u>310</u>π0

148m

* normal conducting!

Excite the Modes while Measuring S₁₁



- H-field on the cavity rim using a inductive coupling loop
 - Bend the center conductor to a closed loop connected to ground

Measurement of Frequency and Q-value





Identify the correct (TM_{010}) mode frequency

- Introduce a small perturbation, e.g. metallic rod or wire on the z-axis and observe the shift of the mode frequencies
- **Calibrate the VNA and measure** S₁₁
 - Tune the coupling loop for critical coupling
 - Display the resonant circle in the Smith chart using a sufficient number of points

The Equivalent Circuit of a Resonant Mode



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Input Impedance in the Complex Z-Plane



Useful Formulas of the Equivalent Circuit



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The Quality Factor (Q-Value)

The quality (Q) factor of a resonant circuit is defined as ratio of the stored energy U over the energy dissipated P in one oscillation cycle:

 $Q = 2\pi \frac{\text{energy stored}}{\text{energy dissipated in 1 cycle}}$

The *Q*-factor of an impedance loaded resonator:

- Q₀: unloaded Q-value of the unperturbed system
- Q_L: loaded Q-value, e.g. measured with the impedance of the connected generator
- *Q_{ext}*: external Q-factor, representing the effects of the external circuit (generator and coupling circuit)

Q-factor and bandwidth

This is how we actually "measure" the Q-factor!

$$Q = \frac{f_{res}}{f_{BW}} \quad \text{with:} \quad f_{BW} = f_{+3dB} - f_{-3dB}$$

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WresU

Ρ

tune k for critical coupling: $Q_0 = Q_{ext}$

 $\Rightarrow Q_0 = 2 Q_L$

With Q_L being our measured Q-value

Q-factor from S₁₁ Measurement



Correct for the uncompensated effects of the coupling loop

Electrical length adjustment: "straight" \(\mathcal{J}\){Z}\(f)\)

Adjust the locus circle to the detuned short location

Phase offset

Verify no evanescent fields penetrating outside the beam ports

 i.e. no frequency shifts if the boundaries at the beam ports are altered



Frequency marker points in the Smith chart:

- $f_{1,2}$: $\Im{S_{11}} = max$. to calculate Q_L
- $f_{3,4}$: $Y = \Re \pm j$ to calculate Q_{ext}
- $f_{5,6}$: $\Re\{Z\} = \Im\{Z\}$ to calculate Q_0

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R/Q Measurement – Slater's Theorem

Remember from the equivalent circuit:

transit time related

(metallic ellipsoid, e.g. syringe needle

of half length *l* and radius *a*)

$$\frac{R}{Q} = \frac{\frac{V_{acc}^2}{2P_d}}{\frac{\omega_{res}U}{P_d}} = \frac{V_{acc}^2}{2\omega_{res}U} \quad \text{with:} \quad V_{acc} = \left| \int E_z(z) \cos\left(\frac{\omega z}{\beta c_0}\right) dz \right|$$

 V_{acc} is based on the integrated longitudinal E-field component E_z along the z-axis (x = y = 0)

Based on Slater's perturbation theorem:

$$\frac{\Delta f}{f_{res}} = \frac{1}{U} \Big[\mu \left(k_{\parallel}^{H} |H_{\parallel}|^{2} + k_{\perp}^{H} |H_{\perp}|^{2} \right) - \varepsilon \left(k_{\parallel}^{E} |E_{\parallel}|^{2} + k_{\perp}^{E} |E_{\perp}|^{2} \right) \Big]$$

- Resonance frequency shift due to a small perturbation object, expressed in longitudinal and transverse E and H field components
- k: coefficients proportional to the electric or magnetic polarizability of the perturbation object (here: only k_{\parallel}^{E} for a longitudinal metallic object)

E-field characterization along the z-axis with: $k_{\parallel}^E = \frac{\pi}{3} l^3 \left[\sinh^{-1} \left(\frac{2}{3\pi} \frac{l}{a} \right) \right]^{-1}$

$$E(z) = \sqrt{\frac{\Delta f(z)}{f_{res}} \cdot \frac{-1}{k_{\parallel}^{E} \varepsilon_{0}}}$$

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 V^2 /

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R/Q Measurement - Bead Pull Method







E-field characterization by evaluating



- The frequency shift (S₁₁ reflection measurement with a single probe) or
- The phase shift ϕ at f_{res} (S_{21} transmission measurement with 2 probes)

Exercise with a manual bead-pull through a known cavity

- requires: fishing wire, syringe needle, ruler and VNA
- Compare the measured E_z at the maximum f or ϕ shift (in the center of the cavity) with the theoretical estimation (e.g. numerical computed value)

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Where to go from here ... ?!

Setup your own mode characterization experiment

- Start with a simple analytically solvable structure, e.g. brick-style or cylindrical ("pillbox") resonator
- Unfortunately you need to go through the math of the modal expansion of the vector potential Ψ...☺

Laplace equation:

$$\Delta \Psi + k_0^2 \varepsilon_r \mu_r \Psi = 0$$

Product ansatz (*Cartesian* coordinates): $\Psi = X(x)Y(y)Z(z)$

General solution (field components):

 $\Psi = \begin{cases} A\cos(k_x x) + B\sin(k_x x) \\ \acute{A}e^{-jk_x x} + \acute{B}e^{-jk_x x} \end{cases} \begin{cases} C\cos(k_y y) + D\sin(k_y y) \\ \acute{C}e^{-jk_y y} + \acute{D}e^{-jk_y y} \end{cases} \begin{cases} E\cos(k_z z) + F\sin(k_z z) \\ \acute{E}e^{-jk_z z} + \acute{F}e^{-jk_z z} \end{cases}$

 $k_0 = \frac{2\pi}{\lambda_0}$

Eigen frequencies:

$$f_{mnp} = \frac{c_0}{2\pi\varepsilon_r\mu_r} \sqrt{\left(\frac{m\pi}{a}\right)^2 + \left(\frac{n\pi}{b}\right)^2 + \left(\frac{p\pi}{c}\right)^2} \qquad k_x = \frac{m\pi}{a} \quad k_y = \frac{n\pi}{b} \quad k_z = \frac{p\pi}{c}$$

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а

standing waves

travelling

waves

 $k_0^2 = \omega^2 \varepsilon_0 \mu_0$ k_0 : free space wave number

 $k_x^2 + k_y^2 + k_z^2 = k_0^2 \varepsilon_r \mu_r$

separation condition:

 λ_0 : free space wave length

Pillbox Eigenmodes

Same procedure, but now with cylindrical functions (3)(3)

Product ansatz (cylindrical coordinates): separation condition: $\Psi = R(\rho)F(\varphi)Z(z)$ $k_r^2 + k_z^2 = k_0^2 \varepsilon_r \mu_r$ standing waves General solution (field components): $\Psi = \begin{cases} A J_m(k_r\rho) + B N_m(k_r\rho) \\ \dot{A}H_m^{(2)}(k_r\rho) + \dot{B}H_m^{(2)}(k_r\rho) \end{cases} \begin{cases} C \cos(m\varphi) + D \sin(m\varphi) \\ \dot{C}e^{-jm\varphi} + \dot{D}e^{-jm\varphi} \end{cases} \begin{cases} E \cos(k_z z) + F \sin(k_z z) \\ \dot{E}e^{-jk_z z} + \dot{F}e^{-jk_z z} \end{cases} \checkmark$ travelling J_m , N_m , $H_m^{(1,2)}$: cylindical functions (*Bessel*, *Hankel*, *Neumann*) waves see Abramowitz and Stegun **Eigen frequencies:** $f_{TMmnp} = \frac{c_0}{2\pi\varepsilon_r\mu_r} \left| \left(\frac{j_{mn}}{r}\right)^2 + \left(\frac{p\pi}{h}\right)^2 \right| = \int f_{TEmnp} = \frac{c_0}{2\pi\varepsilon_r\mu_r} \left| \left(\frac{j'_{mn}}{r}\right)^2 + \left(\frac{p\pi}{h}\right)^2 \right|$

 j_{mn} being the n^{th} root of $J_m(x)$ j'_{mn} being the n^{th} root of $J'_m(x)$

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Compare your Results

Analytical – Numerical – Measurement

There is also an analytical expression for the R/Q of the TM_{010} mode of a cylindrical resonator:

$$\frac{R}{Q} = \frac{4 \eta}{j_{01}^3 \pi J_1^2(j_{01})} \frac{\sin^2\left(\frac{J_{01}}{2}\frac{h}{r}\right)}{h/r} \approx 128 \frac{\sin^2\left(1.2024 \ h/r\right)}{h/r} \qquad \eta = \sqrt{\frac{\mu_0}{\varepsilon_0}} \approx 377$$
...and for the $Q_0 = \frac{r}{\delta} \left[1 + \frac{r}{h}\right]^{-1}$ skin depth: $\delta = \frac{2}{(\omega_{\text{max}}\sigma)^{1/2}}$

- There are student versions for 3D numerical EM software available
 - Visualize E and H fields to ensure you got the expected results!
- Remember: f_{res} and R/Q are only determined by the geometry of the cavity, the Q-factor however depends on the material properties (conductivity!)
 - The results of the Q-factor may vary between measurement and computation
- Don't forget to compute the values of the equivalent circuit!

 $\sqrt[20]{0} \delta \left[\frac{1}{h} \right]$

- Make use of mode charts to understand the order of the eigen-frequencies
- If the phase-shift method is used to measure the R/Q with the bead-pull, set the VNA to "Zero Span" at f_{TM010} and use a very weak coupling to stay precisely on the eigen-frequency
 - Compare the measured phase before and after the bead-pull! If the value has changed the phase drifted because of temperature effects! Perform the bead-pull at a faster pace!

 $\omega_{res}\sigma\mu$

Beam Coupling Impedance

The wake potential

Lorenz force on q₂ by the wake field of q₁:

$$\vec{F} = \frac{d\vec{p}}{dt} = q_2 \left(\vec{E} + c_0 \vec{e}_z \times \vec{B}\right)$$

• Wake potential of a structure, e.g. a discontinuity driven by q_1



$$\vec{w}(x_1, y_1, x_2, y_2, s) = \frac{1}{q_1} \int_{-\infty \text{ (or 0)}} dz \left[\vec{E}(x_2, y_2, z, t) + c_0 \vec{e}_z \times \vec{B}(x_2, y_2, z, t) \right]_{t=(s+z)/c}$$

 $+\infty$ (orL)

Beam coupling impedance

Frequency domain representation of the wake potential

$$Z(x_1, y_1, x_2, y_2, \omega) = -\frac{1}{c_0} \int_{-\infty}^{\infty} ds \, \vec{w}(x_1, y_1, x_2, y_2, s) e^{-j\omega s/c_0}$$

Can be decomposed in longitudinal Z_{\parallel} and transverse Z_{\perp} components (*Panofsky-Wenzel* theorem) Resonant structures, i^{th} mode: $R_{sh,i} = Z_{\parallel,i} = \frac{2k_{loss,i}Q_i}{2k_{loss,i}Q_i}$

ωi

0

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Stretched-Wire Z_{\parallel} Measurement **Formulas: VNA** $\Theta = 2\pi \frac{L}{\lambda}$ Normalized electrical length: S21 meas. Lumped impedance formula Z_0 Z_0 •P1 P20- $Z_{\parallel} = 2Z_{pipe} \frac{1 - S_{21}}{S_{21}} \quad \substack{\Theta \leq 1 \\ L < D_{pipe}}$ Log formula Z_{pipe} $Z_{\parallel} = -2Z_{pipe} \ln S_{21}$ -10dB Improved log formula $Z_{\parallel} = -2Z_{pipe} \ln S_{21} \left(1 + j \frac{\ln S_{21}}{2\Theta} \right)$ R_{match} $R_{match} = Z_{pipe} - Z_0$ stretched wire REF Transmission $S_{21} = \frac{S_{21,DUT}}{S_{21,REF}}$ coefficient **Circular beam pipe** impedance $Z_{pipe} = \frac{\eta_0}{2\pi\sqrt{\varepsilon_r}} \ln \frac{D}{d} \cong 60 \ \Omega \ln \frac{D_{pipe}}{d_{wire}}$ absorbing foam

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I could not cover everything...

• Other VNA "goodies"...

- 4-port VNA with "virtual" ports, e.g. differential S-parameters
- Power sweep for 1 dB compression point RF amplifier analysis

Spectrum analysis

- Modulation, demodulation
- Intermodulation measurements (IP3) and other non-linear effects
- Noise and noise figure analysis
- More on wakefields and beam impedance measurements
 - Introduced the stretched wire method, but what about Z_{\perp} ?
 - Material and surface characterization
 - Measurements on waveguides and periodic structures

A few more examples are found in the Appendix

- Also, please study the supplied reports
- Try to setup and execute some of the CAS RF experiments
- Watch the movies mentioned on slide 26!

More Options to learn...







Shis CAS RF practical training

If you did not sign up for RF, pass by our training room and have a look...

CAS Special Topic: RF

March/April 2020, Kaunas, Lithuania

JUAS

 Open air tutorial session in Archamps (nice weather in February!)

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Appendix A: Definition of the Noise Figure



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Measurement of Noise Figure (using a calibrated Noise Source)



Examples of 2-ports (2)



The left waveguide uses a TE₁₀ mode (=vertically polarized H field). After transition to a circular waveguide, the polarization of the mode is rotated counter clockwise by 45° by a ferrite. Then follows a transition to another rectangular waveguide which is rotated by 45° such that the forward wave can pass unhindered. However, a wave coming from the other side will have its polarization rotated by 45° clockwise as seen from the right hand side.

3-Port Examples (2)

Practical implementations of circulators:



A circulator contains a volume of ferrite. The magnetically polarized ferrite provides the required non-reciprocal properties, thus power is only transmitted from port 1 to port 2, from port 2 to port 3, and from port 3 to port 1.

3-Port Examples (3)

E plane waveguide The T splitter is reciprocal and lossless but not matched at all ports. Using the losslessness condition and symmetry considerations one finds for E and H plane морег 🛞 зекнуг splitters H plane waveguide Port 2 Port 1 $\frac{1}{\sqrt{2}}$ H-plane splitter $S_H = \frac{1}{2} \left| -1 \right|$ Port 3 Note: change in sign of wave going left or right $\sqrt{2}$ **E-plane splitter** $S_E = \frac{1}{2} \begin{vmatrix} 1 & 1 & -\sqrt{2} \\ \sqrt{2} & -\sqrt{2} & 0 \end{vmatrix}$ Port 2 Port 1 Port 3

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4-Port Examples (2)

Magic-T also referred to as 180° hybrid:



The H-plane is defined as a plane in which the magnetic field lines are situated. E-plane correspondingly for the electric field.



Port 1

Port 4 (E-Arm) Port 2 Port 3 (H-Arm)

Can be implemented as waveguide or coaxial version. Historically, the name originates from the waveguide version where you can "see" the horizontal and vertical "T".

Pathing through a 2-port (1)



Pathing through a 2-port (2)



Appendix C: T matrix

The T-parameter matrix is related to the incident and reflected normalised waves at each of the ports.

$$\begin{pmatrix} b_1 \\ a_1 \end{pmatrix} = \begin{bmatrix} T_{11} & T_{12} \\ T_{21} & T_{22} \end{bmatrix} \begin{pmatrix} a_2 \\ b_2 \end{pmatrix}$$

T-parameters may be used to determine the effect of a cascaded 2-port networks by simply multiplying the individual T-parameter matrices:
$$[T] = \begin{bmatrix} T^{(1)} \end{bmatrix} \begin{bmatrix} T^{(2)} \end{bmatrix} \dots \begin{bmatrix} T^{(N)} \end{bmatrix} = \prod_{N} \begin{bmatrix} T^{(1)} \end{bmatrix} \qquad \stackrel{b_1}{\underset{N}{\longrightarrow}} \underbrace{T^{(1)}}_{a_1} \underbrace{a_2}_{b_2} \underbrace{b_3}_{a_3} \underbrace{T^{(2)}}_{b_4} \underbrace{a_4}_{b_4}$$

T-parameters can be directly evaluated from the associated S-parameters and vice versa.
From S to T:
$$[T] = \frac{1}{S_{21}} \begin{bmatrix} -\det(S) & S_{11} \\ -S_{22} & 1 \end{bmatrix} \qquad [S] = \frac{1}{T_{22}} \begin{bmatrix} T_{12} & \det(T) \\ 1 & -T_{21} \end{bmatrix}$$

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Appendix D: A Step in Characteristic Impedance (1)

Consider a connection of two coaxial cables, one with $Z_{C,1} = 50 \Omega$ characteristic impedance, the other with $Z_{C,2} = 75 \Omega$ characteristic impedance.

1 Connection between a 50Ω and a 75 Ω cable. We assume an infinitely short cable length and just look at the junction. $Z_{C,1} = 50\Omega$ Connection between a 50Ω and a 75 Ω cable. $Z_{C,2} = 75\Omega$ $Z_{C,2} = 75\Omega$

Step 1: Calculate the reflection coefficient and keep in mind: all ports have to be terminated with their respective characteristic impedance, i.e. 75 Ω for port 2.

$$\Gamma_1 = \frac{Z - Z_{C,1}}{Z + Z_{C,1}} = \frac{75 - 50}{75 + 50} = 0.2$$

Thus, the voltage of the reflected wave at port 1 is 20% of the incident wave, and the reflected power at port 1 (proportional Γ^2) is $0.2^2 = 4\%$. As this junction is lossless, the transmitted power must be 96% (conservation of energy). From this we can deduce $b_2^2 = 0.96$. But: how do we get the voltage of this outgoing wave?

Example: a Step in Characteristic Impedance (2)

<u>Step 2</u>: Remember, *a* and *b* are power-waves, and defined as voltage of the forward- or backward traveling wave normalized to $\sqrt{Z_c}$.

The tangential electric field in the dielectric in the 50 Ω and the 75 Ω line, respectively, must be continuous.



Example: a Step in Characteristic Impedance (3)

Once we have determined the voltage transmission coefficient, we have to normalize to the ratio of the characteristic impedances, respectively. Thus we get for

$$S_{12} = 1.2 \sqrt{\frac{50}{75}} = 1.2 \cdot 0.816 = 0.9798$$

We know from the previous calculation that the reflected <u>power</u> (proportional Γ^2) is 4% of the incident power. Thus 96% of the power are transmitted. Check done $S_{12}^{2} = 1.44 \frac{1}{1.5} = 0.96 = (0.9798)^{2}$

$$S_{22} = \frac{50 - 75}{50 + 75} = -0.2$$
 To be compared with S11 = +0.2!

Example: a Step in Characteristic Impedance (4)

Visualization in the Smith chart: As shown in the previous slides the voltage of the transmitted wave is $V_{t} = a + b = 1.2$ $V_t = a + b$, with t = 1 + Γ and subsequently the current is *-b* ∦ *b* = +0.2 $I_t Z = a - b$ $I_{t}Z = a - b.$ Remember: the reflection coefficient Γ is incident wave a = 1defined with respect to voltages. For currents the sign inverts. Thus a positive reflection coefficient in the normal definition leads to a subtraction of currents or is negative with respect to current. Note: here Z_{load} is real

Example: a Step in Characteristic Impedance (5)



Appendix E: Navigation in the Smith Chart (1)

points

This is a "bilinear" transformation with the following properties:

- generalized circles are transformed into generalized circles
 - circle \rightarrow circle
 - straight line \rightarrow circle
 - circle → straight line
 - straight line → straight line
- angles are preserved locally

a circle with infinite radius a circle is defined by 3 points a straight line is defined by 2

a straight line is nothing else than

Navigation in the Smith Chart (2)



Navigation in the Smith Chart (3)



Appendix F: The RF diode (1)

- We are not discussing the generation of RF signals here, just the detection
- Basic tool: fast RF* diode

 (= Schottky diode)

 In general, Schottky diodes are
 fast but still have a voltage

 dependent junction capacity
 (metal semi-conductor junction)

Equivalent circuit:





A typical RF detector diode

Try to guess from the type of the connector which side is the RF input and which is the output



*Please note, in this lecture we will use RF (radio-frequency) for both, the RF and the microwave range, since there is no defined borderline between the RF and microwave regime.

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The RF diode (2)

Characteristics of a diode:

The current as a function of the voltage for a barrier diode can be described by the Richardson equation:



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The RF diode (3)

This diagram depicts the so called square-law region where the output voltage (V_{Video}) is proportional to the input power

Since the input power is proportional to the square of the input voltage (V_{RF}^2) and the output signal is proportional to the input power, this region is called square- law region.

In other words: $V_{Video} \sim V_{RF}^2$



 The transition between the linear region and the square-law region is typically between -10 and -20 dBm RF power (see diagram).

The RF diode (5)

Due to the square-law characteristic we arrive at the thermal noise region already for moderate power levels (-50 to -60 dBm) and hence the V_{Video} disappears in the thermal noise

This is described by the term tangential signal sensitivity (TSS) where the detected signal (Observation BW, usually 10 MHz) is 4 dB over the thermal noise floor



Appendix G: The RF mixer (1)

- For the detection of very small RF signals we prefer a device that has a linear response over the full range (from 0 dBm (= 1mW) down to thermal noise = -174 dBm/Hz = 4.10⁻²¹ W/Hz)
 - It is called "RF mixer", and uses 1, 2 or 4 diodes in different configurations (see next slide)
- Together with a so called LO (local oscillator) signal, the mixer works as a signal multiplier, providing a very high dynamic range since the output signal is always in the "linear range", assuming the mixer is not in saturation with respect to the RF input signal (For the LO signal the mixer should always be in saturation!)
- The RF mixer is essentially a multiplier implementing the function

 $f_1(t) \cdot f_2(t)$ with $f_1(t) = RF$ signal and $f_2(t) = LO$ signal

 $a_1 \cos(2\pi f_1 t + \varphi) \cdot a_2 \cos(2\pi f_2 t) = \frac{1}{2} a_1 a_2 [\cos((f_1 + f_2)t + \varphi) + \cos((f_1 - f_2)t + \varphi)]$

Thus we obtain a response at the IF (intermediate frequency) port as sum and difference frequencies of the LO and RF signals

The RF mixer (2)

Examples of different mixer configurations



A typical coaxial mixer (SMA connector)

The RF mixer (3)

Response of a mixer in time and frequency domain:



The RF mixer (4)

Dynamic range and IP3 of an RF mixer

The abbreviation IP3 stands for third order intermodulation point, where the two lines shown in the right diagram intersect. Two signals $(f_1, f_2 > f_1)$ which are closely spaced by Δf in frequency are simultaneously applied to the DUT. The intermodulation products appear at + Δf above f_2 and at - Δf below f_1 .

This intersection point is usually not measured directly, but extrapolated from measurement data at much lower power levels to avoid overload and/or damage of the DUT.

